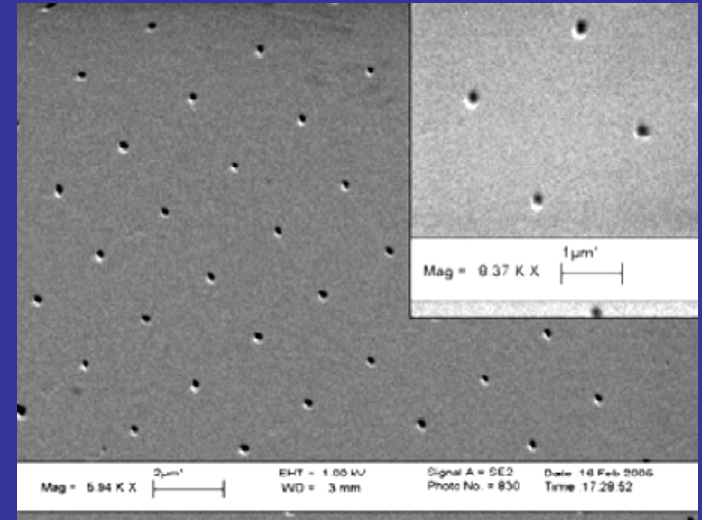
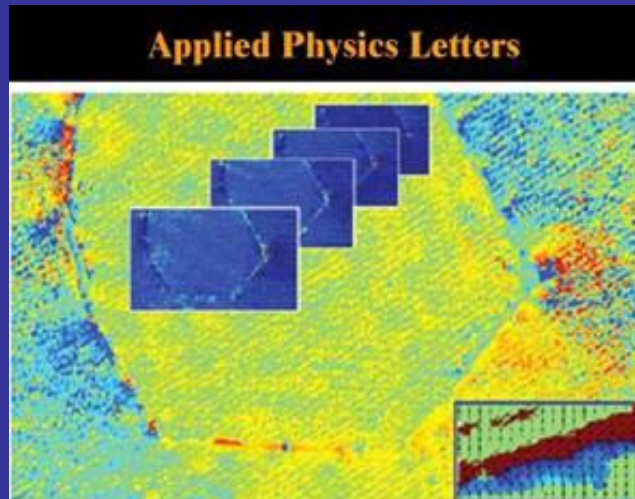


Characterization of materials and processes

M. Paturzo, et al. *APL* **88**, 151918 06 (2006)

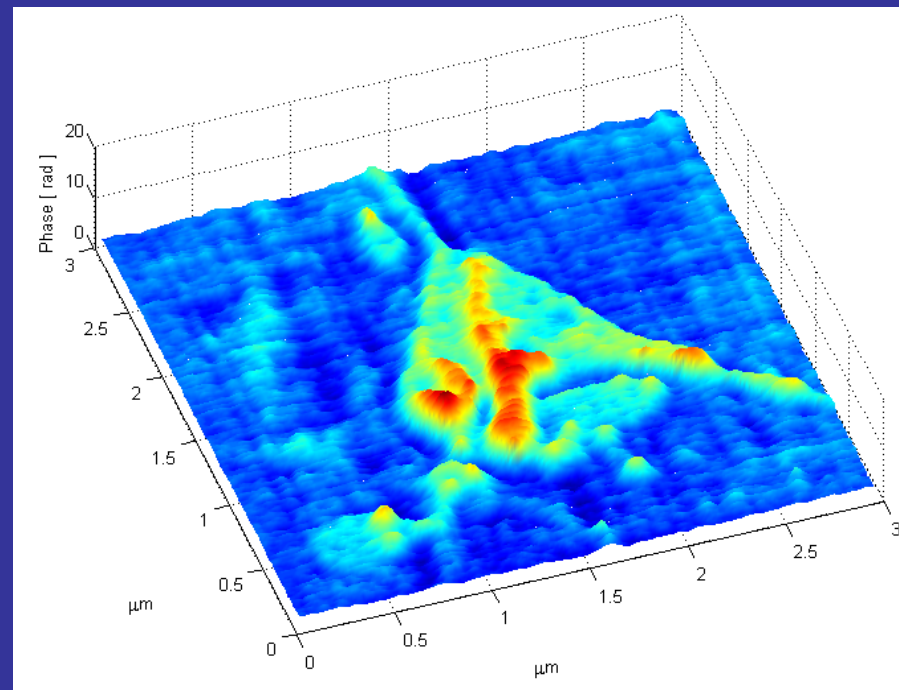
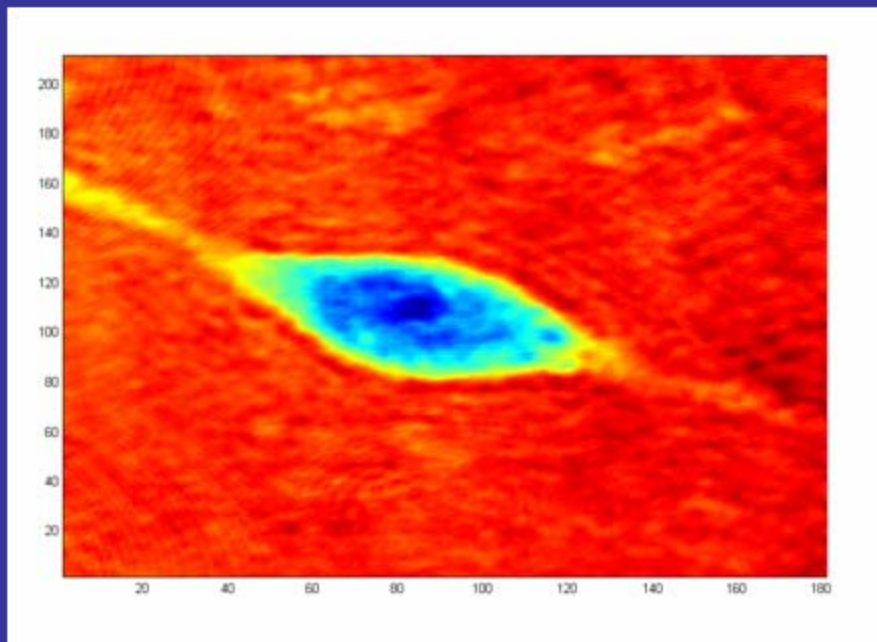
P. Ferraro & S. Grilli *APL*
89, 133111 (2006).



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Optics Letters, **31**, 3164 (2006)
Optics Letters **31**, 3597-3599 (2006).

Quantitative Phase-contrast Microscopy (QPM) of *in-vitro* cells



SPIE Newsroom in Biomedical Optics & Medical Imaging (2007)

- P. Ferraro, et al. **Opt. Lett.** **31** 1405 (2006)
- L. Miccio, et al. **App. Phys. Lett.** **90** 041104 (2007)
- P. Ferraro et al. **Opt. Express**, in press (2007)

*4 Patents Licensed to
a US company about
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Characterization by Interference Microscopy

Amplitude and phase reconstruction of photorefractive spatial bright-soliton in Lithium Niobate

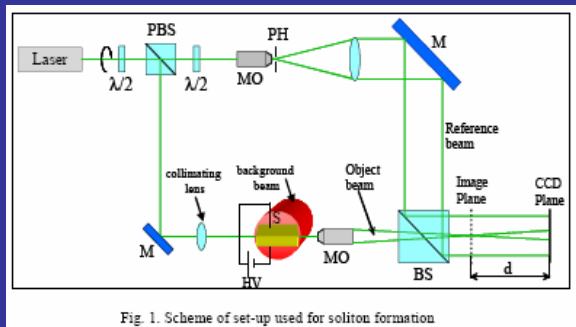
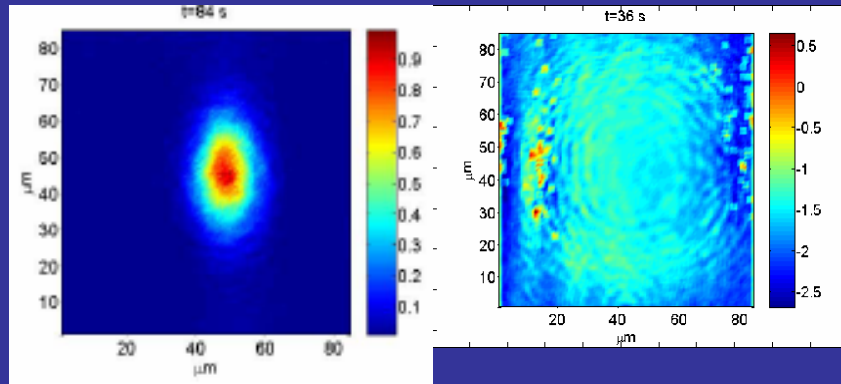
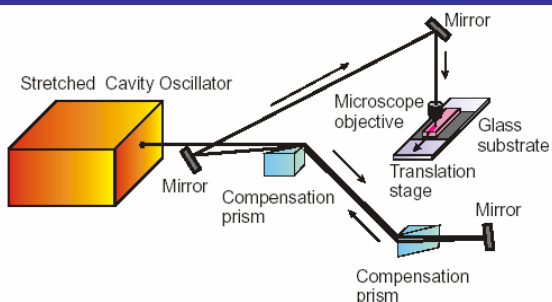


Fig. 1. Scheme of set-up used for soliton formation

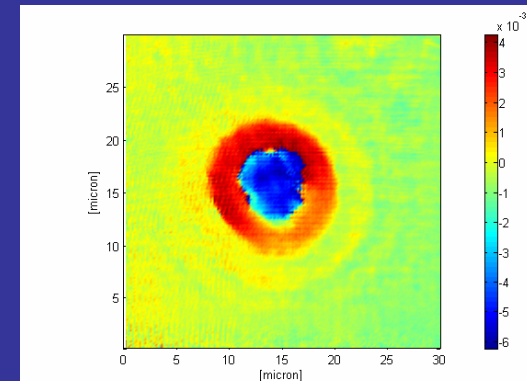
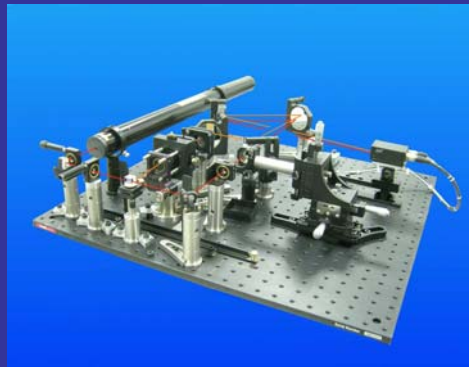
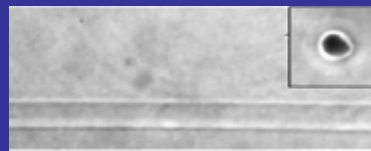


Maps of the beam intensity during soliton formation and phase distribution computed by the numerical reconstruction of digitally recorded holograms
 al., Optics Express 15, 8243 (2007)

Characterization of optical waveguides by digital holographic microscopy



Optical waveguide writing setup



Map of the refractive index distribution written in glass substrate (Alkali-zinc silicate Schott IOG10), Opt. Express 13, 512 (2005)